Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/751,172	HAN, JAE-WON
Examiner	Art Unit
Ha T. Nguyen	2812

	SEAR	CHED	
Class	Subclass	Date	Examiner
438	682-683	6/15/2005	HN
-	710,745	6/15/2005	HN
-	749	6/15/2005	HN
134	1-1.3	6/15/2005	HN

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NO (INCLUDING SEARCH	TES STRATEGY)
	DATE	EXMR
EAST search	6/15/2005	HN
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